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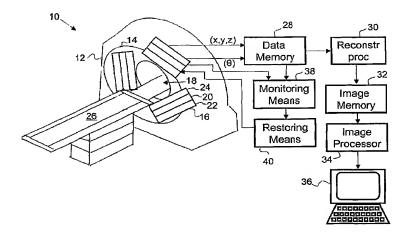
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Declaration under Rule 4.17:

— as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(ii)) for the following designations AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE,

[Continued on next page]

 $\textbf{(54) Title:} \ \textbf{METHOD} \ \textbf{AND} \ \textbf{APPARATUS} \ \textbf{FOR} \ \textbf{REVERSING} \ \textbf{PERFORMANCE} \ \textbf{DEGRADATION} \ \textbf{IN} \ \textbf{SEMI-CONDUCTOR} \ \textbf{DETECTORS}$



(57) Abstract: A system reverses degraded energy resolution of semiconductor radiation detection elements (44) which are used in a radiation detector assembly. A means (38) identifies semiconductor elements which exhibit degraded energy resolution as compared to an initial level of energy resolution after application of the forward bias. A means (40) restores the degraded semiconductor elements to the initial level of energy resolution by applying the reverse bias. A heater (74) accelerates the restoration process by supplying an elevated ambient temperature. A screening means (48) screens new semiconductor elements to identify the elements which are susceptible to degradation. A forward bias is applied by a forward bias means (50) to induce the degradation. A heater (52) increases an ambient temperature to accelerate the performance degradation in the new semiconductor. elements. The identified degradable elements are treated with a reverse bias prior to installation in the detector.



WO 2005/040854 A3

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For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.

Interion nal Application No

	INTERNATIONAL SEARCH RE	FORI	PCT/IB2004	4/052001
A. CLASS	ification of subject matter G01T1/24			
176 /	G01/1/24			
<u>-</u> _	to International Patent Classification (IPC) or to both national class	iffication and IPC	- 10	
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IPC 7	G01T			
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Documenta	tion searched other than minimum documentation to the extent tha	at such documents are include	ded in the fields sear	rched
Electronic d	ata base consulted during the international search (name of data	base and, where practical,	search terms used)	
EPO-In	ternal, WPI Data, PAJ			
C. DOCUME	ENTS CONSIDERED TO BE RELEVANT			
Category °	Citation of document, with indication, where appropriate, of the	relevant passages		Relevant to claim No.
· ·	OCTANICIT M FT AL. HEFFORT OF			1.0.0
X	OSINNSKI M ET AL: "Effects of irradiation on AlGaN/InGaN/GaN	proton green light		1,8,9, 13,21
	emitting diodes"			10,21
	ELECTRONICS LETTERS, IEE STEVEN vol. 33, no. 14, 3 July 1997 (1	AGE, GB, 997-07-03)	Ī	1.
	pages 1252-1254, XP006007673	337 07 03),	-	
	ISSN: 0013-5194			
	The entire document			
Α	US 4 013 485 A (MA ET AL)			1,13
	22 March 1977 (1977-03-22) abstract			
	column 1, line 40 - line 53			:
	column 2, line 39 - line 59 figures			
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X Furthe	er documents are listed in the continuation of box C.	X Patent family me	embers are listed in ar	nnex.
° Special categories of cited documents : "T" later document published after the international filing date				tional filing date
	nt defining the general state of the art which is not ered to be of particular relevance	or priority date and n cited to understand the invention	of in conflict with the he principle or theory	application but underlying the
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"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another		involve an inventive s "Y" document of particular	step when the docum	ient is taken alone
citation or other special reason (as specified) "O" document referring to an oral disclosure, use, exhibition or		cannot be considered document is combine	d to involve an invent	ive step when the
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later than the priority date claimed		"&" document member of		
Date of the actual completion of the international search		Date of mailing of the	international search r	report 06. 06. 2005
17	7 February 2005			
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	ation) DOCUMENTS CONSIDERED TO BE RELEVANT		
Category °	Citation of document, with indication, where appropriate, of the relevant passages		Relevant to claim No.
A	HAMILTON W J ET AL: "VERY HIGH RESOLUTION DETECTION OF GAMMA RADIATION AT ROOM-TEMPERATURE USING P-I-N DETECTORS OF CDZNTE AND HGCDTE" RECORD OF THE NUCLEAR SCIENCE SYMPOSIUM AND MEDICAL IMAGING CONFERENCE SAN FRANCISCO, OCT. 30 - NOV. 6, 1993, NEW YORK, IEEE, US, vol. VOL. 1, 30 October 1993 (1993-10-30), pages 232-235, XP000481346 the entire document		2,8,21
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Information on paterit ramily members

Internation No
PCT/IB2004/052001

2 A1 17-11-1977 5 A1 28-04-1978 0 A 07-11-1977

Form PCT/ISA/210 (patent family annex) (January 2004)



Box II	Observations where certain claims were found unsearchable (Continuation of item 2 of first sheet)
This Inte	ernational Search Report has not been established in respect of certain claims under Article 17(2)(a) for the following reasons:
1.	Claims Nos.: because they relate to subject matter not required to be searched by this Authority, namely:
2.	Claims Nos.: because they relate to parts of the International Application that do not comply with the prescribed requirements to such an extent that no meaningful International Search can be carried out, specifically:
3.	Claims Nos.: because they are dependent claims and are not drafted in accordance with the second and third sentences of Rule 6.4(a).
Box III	Observations where unity of invention is lacking (Continuation of item 3 of first sheet)
This Inter	rnational Searching Authority found multiple inventions in this international application, as follows:
	see additional sheet
1.	As all required additional search fees were timely paid by the applicant, this International Search Report covers all searchable claims.
2	As all searchable claims could be searched without effort justifying an additional fee, this Authority did not invite payment of any additional fee.
3	As only some of the required additional search fees were timely paid by the applicant, this International Search Report covers only those claims for which fees were paid, specifically claims Nos.:
	No required additional search fees were timely paid by the applicant. Consequently, this International Search Report is restricted to the Invention first mentioned in the claims; it is covered by claims Nos.: 1, 2, 8, 9, 13, 21
Remark o	The additional search fees were accompanied by the applicant's protest. No protest accompanied the payment of additional search fees.

FURTHER INFORMATION CONTINUED FROM PCT/ISA/ 210

This International Searching Authority found multiple (groups of) inventions in this international application, as follows:

1. claims: 1,2,8,9,13,21

A semiconductor element consisting of cadmium-zinc-telluride or cadmium-telluride crystals.

2. claims: 3,4

Reversing degradation of semiconductor elements by using reverse biasing.

3. claims: 5-7,20

A pre-use screening means for identifying degraded semiconductor elements.

4. claims: 10-12

A method for generating an alarm when the response of the detector signal degrads.

5. claims: 14-19

A pixel analyser to measure the radiation intensity distribution.